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Application/Control No.	Applicant(s)/Patent under Reexamination
10/672,943	NUNEZ, CHRIS
Examiner	Art Unit
Yicun Wu	2165

SEARCHED				
Class	Subclass	Date	Examiner	
707	1-10, 100- 104.1 200-206	6/6/2006	YW	
715,	515-517	6/6/2006	YW	
715	501	6/6/2006	YW	
711	137	6/6/2006	YW	
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
Inventor search (double patenting) uspto uspgpub epo jpo ibmtech derwent	6/6/2006	YW	
acm leee citeseer Internet Search stratagy attached	6/6/2006	YW	
upilitiel Seul	3/28/07	m	
Consulted Pat Salel			
updated Seah	9/26/07	n	